

# First Announcement

from the International Union of Microbeam Analysis Societies (IUMAS):



## August 2

Saturday workshops on microanalysis techniques, led by renowned experts

EDS • EELS • EPMA • VP-SEM • EBSD • FIB  
SPM • APT • HIM • LA ICP-MS • DTSA-II • SI

## August 3

Sunday opening ceremony & plenary session

Overviews of the current state-of-the-art in key applications areas for microanalysis

## August 4-7

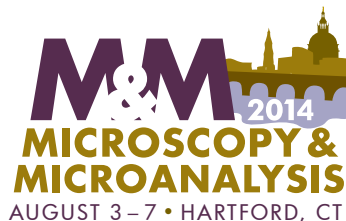
Held in conjunction with the M&M meeting, the largest annual meeting in the field

Symposia with invited & contributed papers in all areas of microscopy & microanalysis

Comprehensive exhibition of the latest instrumentation & accessories



held in conjunction with



## SCIENTIFIC TOPICS

### Microanalysis Instrumentation & Techniques

X-ray microanalysis • Advances in detectors • Cathodoluminescence • High-resolution microanalysis: STEM-EELS & -XEDS • EBSD • Atom probe microscopy • X-ray fluorescence & diffraction microanalysis • High-precision microanalysis: LA ICP-MS / SIMS • Compositional imaging • FIB & related techniques • Correlative microscopy & microanalysis • Tomography • Low energy & advanced SEM techniques • Dynamic & in-situ EM

### Applications Areas

Micro- & nano-particle analysis • Microelectronic materials • Geological materials • Metallurgical materials • Energy-related materials • Catalysis • Cultural heritage materials • Carbon-based materials • Forensic studies • Thin films & coatings

More information at [www.iumas6.org](http://www.iumas6.org)

Pre-registration open!